

April 9, 2003

NEWS AND ANNOUNCEMENTS

Teradyne Introduces Optima 7210™ Optical Process Test (OPT) System

Teradyne announces the availability of the ground-breaking Optima 7210 optical process test (OPT) system for post-placement, in-line defect detection and process measurement. This revolutionary machine vision system replaces user judgment with built-in knowledge of SMD process and variation compensation to enable the completion of production-ready test programs in as little as one hour, shortening manufacturing cycle times, reducing time to first article validation and improving outgoing prototype product quality. To read more about this machine vision system and its use of Configural Recognition™ object recognition and image analysis technology and Teradyne's VARI-Smart™ image compensation software, click here:

http://www.teradyne.com/prods/cbt/news/newsdesk/72news_pr_030331.html

Teradyne Introduces TestStation LH™ In-Circuit Tester – Features Safe, Accurate Testing of Low-Voltage Technologies at Affordable Price

Teradyne announces the immediately availability of the TestStation LH in-circuit test system, a new lower-cost, small footprint, feature scalable, version of Teradyne's popular, award winning TestStation 12X™ product family. Click here to read more about the system features and the SafeTest™ Protection Technology:

http://www.teradyne.com/prods/cbt/news/newsdesk/73news_pr_030331.html

Teradyne Awarded Two Service Excellence Awards at APEX; Customers Commend Teradyne's Assembly Test and Connection Systems Divisions

Teradyne's Assembly Test Division received an award from *Circuits Assembly* magazine in the Electronics Assembly Equipment Suppliers category for electronic assembly equipment. The award recognizes ATD for demonstrating outstanding performance in customer satisfaction. Awards are presented to companies receiving the highest cumulative scores from their customers in the areas of dependability, manufacturing quality, responsiveness to changes and requests, technology and value for the price. To read more about the Service Excellence Awards click here:

http://www.teradyne.com/prods/cbt/news/newsdesk/74news_pr_030404.html

Teradyne's Assembly Test Division – Press Room - * New Feature *****

To learn more about Teradyne and the Assembly Test Division, check out the Press Room where you will find information about Teradyne's tradition of leadership and its culture of innovation. You will also find new product fact sheets and new product photos. Click here to enter the Press Room:

<http://www.teradyne.com/prods/cbt/pressroom/pressroom.html>

UPCOMING EVENTS

Teradyne Users' Group (TUG), Nashville, TN – May 5-7, 2003

To round out the Technical Program scheduled for TUG 2003, on Monday, May 5, from 9:00 a.m. – 10:00 a.m., Dr. Thomas W. Williams will be the keynote speaker at the Users Group. Dr. Williams is a

Synopsys Fellow at Synopsys in Boulder, Colorado. He will be speaking on the topic of, "A DFT History of the Last 25 Years." Teradyne welcomes Dr. Williams to the Users Group. Click here for more information about Dr. Williams and to access complete information about technical program:
<http://www.teradyne.com/prods/tug/t2003keynote.html>

PRODUCT INFORMATION

Teradyne Global Support Services (Assembly Test Division)

Teradyne global support services have been created to help electronics OEMs and contract manufacturers realize their challenging manufacturing objectives and profitability goals. Our worldwide network of regional support and training centers, including our newest state-of-the-art facility in Shanghai, China, are strategically located to offer customers convenient access to a comprehensive range of innovative and cost-effective services, product support, and training programs. For more information Global Support Services, click here:

http://www.teradyne.com/prods/cbt/support/supServ_home.html

TestStudio™ 2003 Release Introduces Exciting New Capabilities * Available for shipment on April 28**

TestStudio 2003 with the Spectrum™ Xpress feature set includes an exciting line of new capabilities to speed test program development and debug, and to make it easier to track, document, and maintain test system assets. This update will be automatically distributed to TestStudio customers with up-to-date Software Support Agreements. To learn more about the capabilities of this release, click here:

http://www.teradyne.com/prods/cbt/products/test-soft/tststud/tststud_ov.html

TPS Converter Studio V2.0 Release Extends Support for Analog Functions * Available for Shipment on April 28**

This latest release of TPS Converter Studio features expanded capabilities for converting analog as well as digital program code from legacy L320-Series Functional Test Platform TPS's to equivalent C code and M9-Series™ Digital Test Binary format. Converted legacy code is ready to run as a standalone executable file or as a test step in TestStudio, the test executive and operating environment for the Spectrum™ 9100-Series Functional Test Platform. For more details about the benefits of this software release, click here:

http://www.teradyne.com/prods/cbt/products/test-soft/tpsconverter/tps_ov.html

Discontinued Products

When discontinued products are no longer available for new purchase from Teradyne, they may be available for purchase through our factory-reconditioned program depending on tester availability. Click here to access information about our factory-reconditioned systems:

http://www.teradyne.com/prods/cbt/products/recon/prod_recon.html

In addition, Teradyne will continue to supply service, spare parts, phone support, and on-site support for some discontinued products. Click here for specific details of each individual product (GR TestStation TSM, GR Viper, GR Pilot):

http://www.teradyne.com/prods/cbt/products/ict/prod_ict_discont.html

Contact Sales – Do You Have a Question?

If you have a question about our products or solutions and would like to request a callback from a Sales Engineer, request product literature, or schedule a product demonstration, use the form located on the following link. You will also find a listing of offices in the Americas, Europe, and Asia as well as a list of Teradyne's Authorized Representatives around the world.

http://www.teradyne.com/prods/cbt/contactus/cnt_f_sales_callback.html

RECENT TECHNICAL PAPERS, ARTICLES, & PUBLICATIONS

"Another Point of View in Machine Vision" by John Arena and Pamela Lipson (*Test & Measurement World; Machine-Vision & Inspection Test Report*, March 1, 2003)

Machine vision systems that rely on brute-force pixel processing will soon be inadequate for many applications. Alternative forms of machine vision promise to advance the state of the art to reduce the spiraling increase in time and computer power required to process images and to eliminate manual programming and tweaking in inspection-system applications. To find out more about these alternatives, click here:

http://www.teradyne.com/prods/cbt/products/library/opt/arena_lipson.pdf

"Gigabit Test Challenges on the Manufacturing Floor" by Kevin L. Paton (*Electronics Engineering Times [EET] Asia*, January 2003)

The increase in production of Gigabit Ethernet (GbE) equipment has resulted in new production test requirements on the manufacturing floor. In the past, all Ethernet products required only electrical tests. Now, test engineers face a standard that supports both electrical and optical capabilities. As a result, a broad understanding of both parametric and functional test requirements is imperative.

Click here for the Chinese version of this article as published in EET China:

http://www.teradyne.com/prods/cbt/products/library/general/Paton_EET_China1.pdf

Click here for the English version of the above article published in EET Asia:

http://www.teradyne.com/prods/cbt/products/library/general/Paton_EET_Asia.pdf

"Optimizing Test Strategies During PCB Design for Boards with Limited ICT Access" by Amit Verma (*Electronica*, February 2003) – Spanish Version

This article investigates the need for distributed test solutions; the data illustrates how design for test (DFT) software can be used to optimize test strategies during PCB design to achieve a balance between test coverage and test cost. To learn how to reduce costs and improve quality by using DFT software tools, click here:

http://www.teradyne.com/prods/cbt/products/library/spectr/Verma_electronica_Feb2003.pdf

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<http://www.teradyne.com/prods/cbt/cbthome.html>

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